Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/750,018	LEE ET AL.	
Examiner	Art Unit	
Binh V. Ho	2163	

SEARCHED					
Class	Subclass	Date	Examiner		
707	103R	6/9/2006	вн		
		-			

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
		- :-		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
707/104.1,103R,1-6,200,2005	6/9/2006	вн		